Application/Control No. Applicant(s)/Patent Under Reexamination 09/940,810 ITOU ET AL Notice of References Cited Examiner Art Unit Page 1 of 1 A. Sefer 2826 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-2001/0004296 06-2001 Van Aerle et al. 359/254 Α US-В US-С US-D US-Ε F US-US-G Н US-1 US-J US-US-Κ L US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY JP 2000-206333 07-2000 Shimadad Ν Japan 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) ٧ W

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